Form PTO-1449

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE ATTY. DOCKET NO.

SERIAL NO. 09/943,180

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APPLICANT Moore et al.

(Use several sheets if necessary) FILING DATE GROUP August 29, 2001 Unknown U.S. PATENT DOCUMENTS \*Examiner Document Date Class Subclass Filing Date Initial Number If Appropriate 3,627,598 12/71 McDonald et al. AB 4,254,161 03/81 Kemlage AC4,262,631 04/81 Kubacki ΑD 4,435,447 3/84 Ito et al. RM ΑE 4,882,649 11/89 Chen et al. fur ÀF Nishioka et al. 4,891,684 01/90 AG 4,980,307 12/90 Ito et al. RMR Ellul et al. ΑH 4,996,081 02/91 5,026,574 06/91 Economu et al. ΑI 5,032,545 07/91 ΑJ Doan et al. ΑK 5,051,794 09/91 Могі AL 5,142,438 08/92 Reinberg et al. FOREIGN PATENT DOCUMENTS Subclass Translation Document Date Country Number Yes No PUR WO 96/39713 PCT Wristers et al. AM ΑN ΑO ΑP AQ OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) Wolf Stanley, "Silicon Processing for the VLSI Era", vol. 2, pp. 188-189, 194-195, 609-614, 1990. AR Wolf, Stanley, "Silicon Processing for the VLSI Era", vol. 2, pp. 212-213, 1990. AS UMI ΑT Wolf, Stanley, "Silicon Processing for the VLSI Era", vol. 3, pp. 648-649, 1995. SANS DATE CONSIDERED **EXAMINER** outlem \*EXAMINER: Initial if reference considered, whether of not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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PUNP	AE	5,324,679	06/94	Kim et al.		/	/		
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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. MI22-1776

SERIAL NO. 09/943,180

LIST OF ART CITED BY APPLICANT

(Use several sheets if necessary)

FILING DATE August 29, 2001

APPLICANT Moore et al.

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PAMP	AC	5,685,949	11/97	Yashima			_			
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